Sheet 1 of 1 **FORM PTO-1449** INFORMATION DISCLOSURE Atty Docket No. : 29287/137 Serial No. STATEMENT BY APPLICANT(S) Inventors : HANZAWA, et al. Filed : 25 June 2003 Group Art Unit : 2818 Examiner : Viet Q. Nguyen **U.S. PATENT DOCUMENTS** Patent Patent Class/ Examiner Filing Initial <u>Number</u> <u>Date</u> Subclass Date <u>Name</u> 6,452,858 09-2002 HANZAWA, et al. 365/230.06 6.545.897 04-2003 FUJISAWA, et al. 365/230.08 6,545,525 04-2003 ITOH, et al 327/524 2001/0028581 10-2001 YANAGISAWA, et al365/189.05 07-2001 2001/0009519 FUJISAWA et al. 365/51 2001/0001598 05-2001 NARUI, et al. 365/149 6,535,435 03-2003 TANAKA, et al. 365/189.09 SEKIGUCHI, et al. 365/72 6,501,672 12-2002 6,480,425 11-2002 YANAGISAWA, et al365/189.05 6,452,858 09-2002 HANZAWA, et al. 365/230.06 **FOREIGN PATENT DOCUMENTS** Examiner Document Class/ **Translation** Initial Number Subclass Yes No Date Country **OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.) Examiner Initial VIET Q. NGUYEN PRIMARY EXAMINER DATE CONSIDERED **EXAMINER** 

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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

# INFORMATION DISCLOSURE STATEMENT BY APPLICANT **PTO FORM 1449**

ATTY. DOCKET NO. 29287/137	SERIAL NO. (Con of 10/201,317)		
APPLICANT HANZAWA et al.			
FILING DATE Viet D. Nguyen (Anticipated)	GROUP 2918 (Anticipated)		

#### **U. S. PATENT DOCUMENTS**

EXAMINER INITIAL	PATENT NUMBER	PATENT DATE	NAME	CLASS	SUBCLASS	FILING DATE
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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	YES	NO
W	JP 02001195879A	07/01	Japan				
W	JP 407057461 A	03/95	Japan				_
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## **VIET Q. NGUYEN** OTHER DOCUMENTS PRIMARY EXAMINER

EXAMINER INITIAL	AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.
W	IEEE International Solid-State Circuits Conference, Digest of Technical Papers, 1972, pp. 10-11.*
W	IEE Electronics Letters, May 13, 1999, Vol. 35, No. 10, pp. 848-850.*
N	European Solid-State Circuits Conference, Digest of Technical Papers, 1992, pp. 131-134.*
W	IEEE Journal of Solid-State Circuits, May 2000, Vol. 35, No. 5, pp. 691-695.

<sup>\*</sup>Mentioned in the Specification

EXAMINER	1/.	Nowiga	DATE CONSIDERED 8/24/09		
EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.					
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